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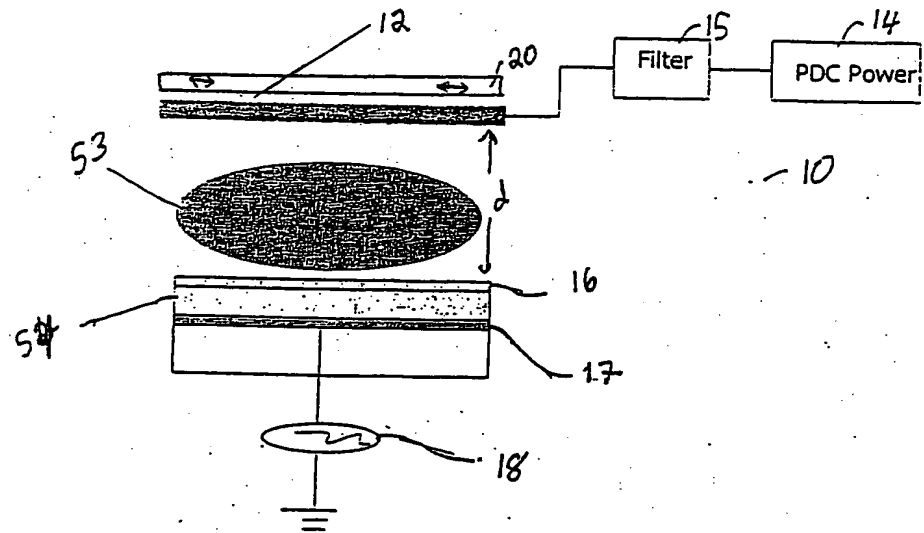


Figure 1A

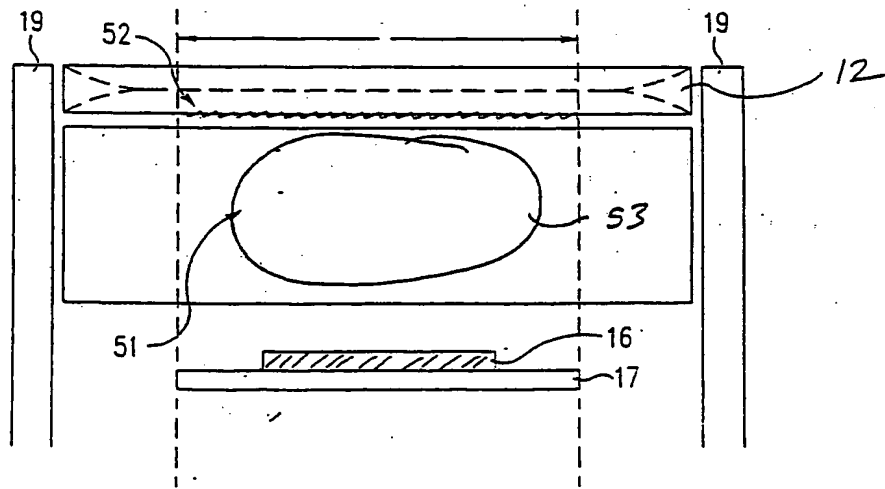


FIG. 1B

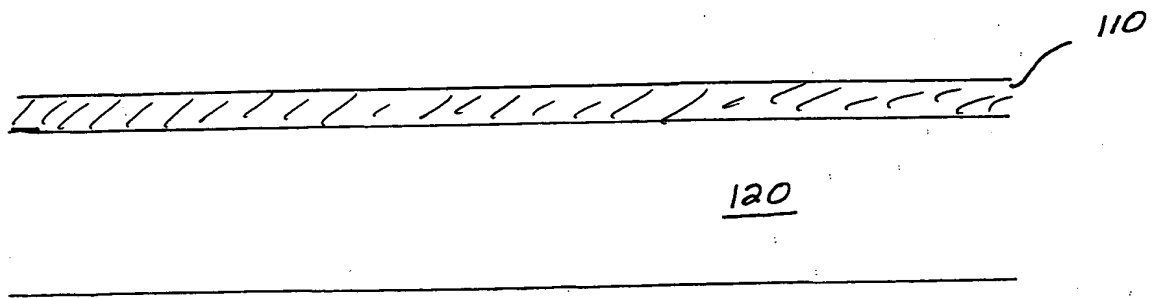


Figure 1C

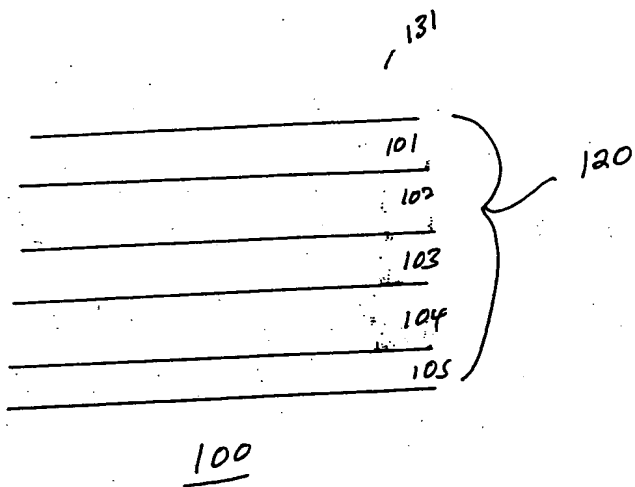


Figure 2A

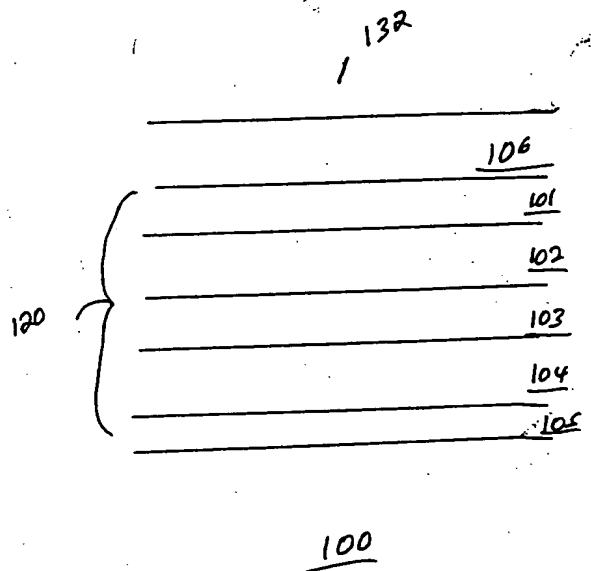


Figure 2B

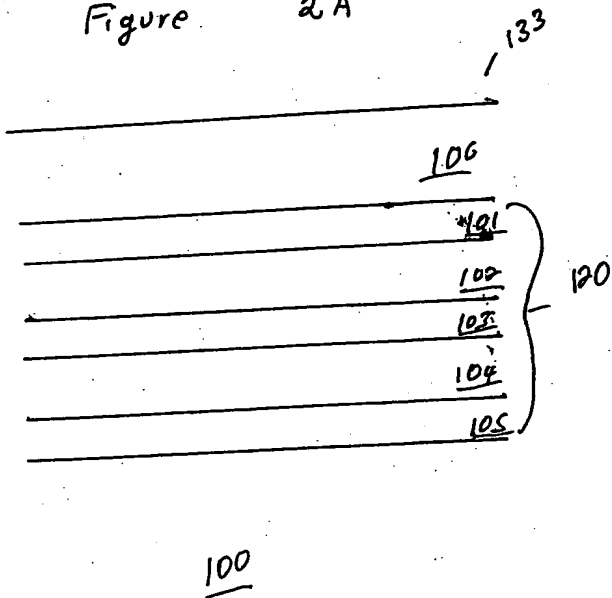


Figure 2C

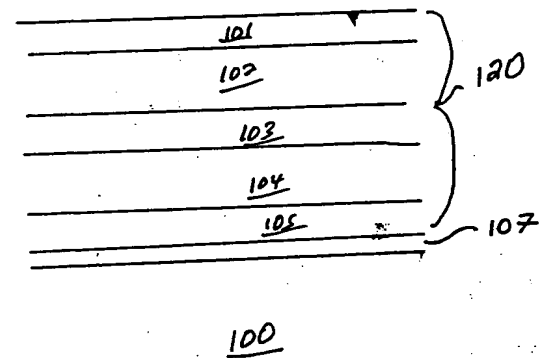


Figure 2D

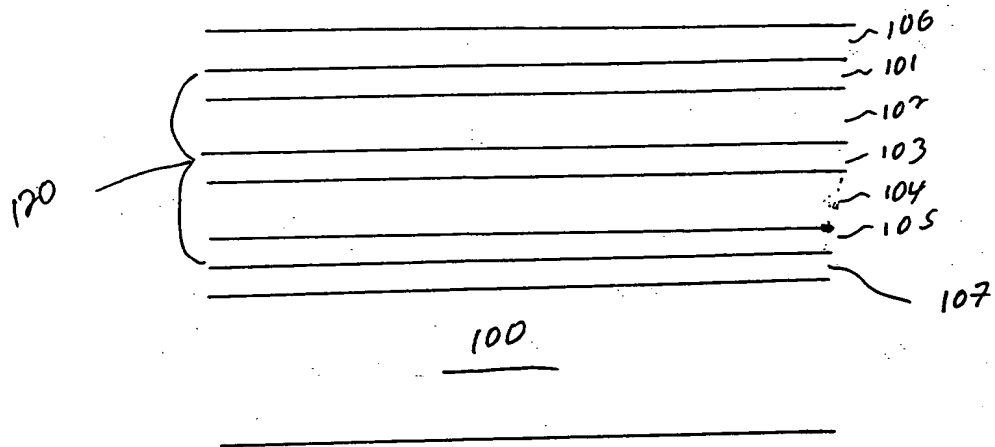
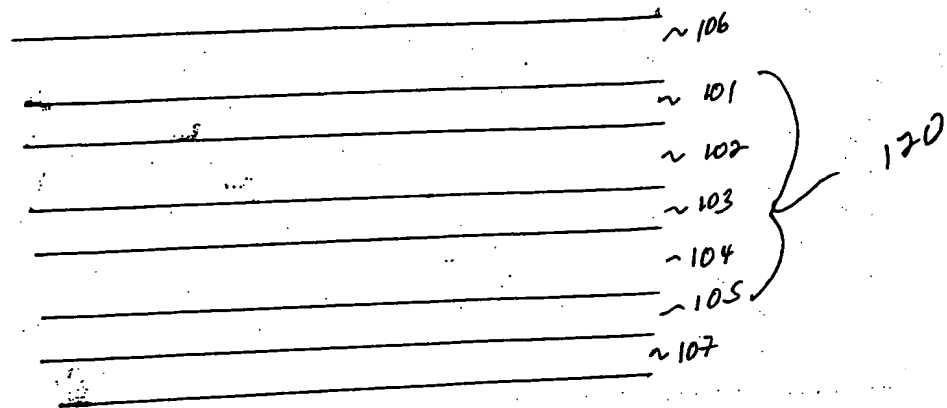


Figure 2E



100

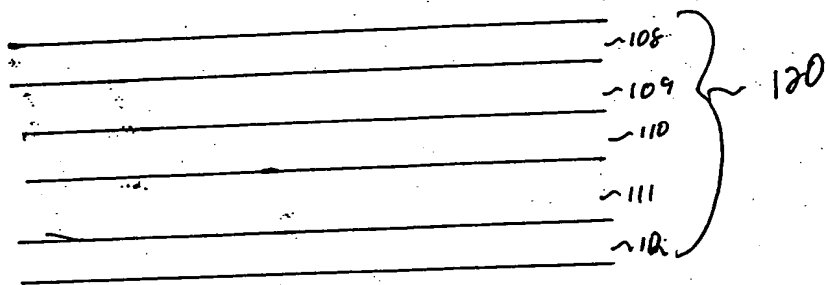


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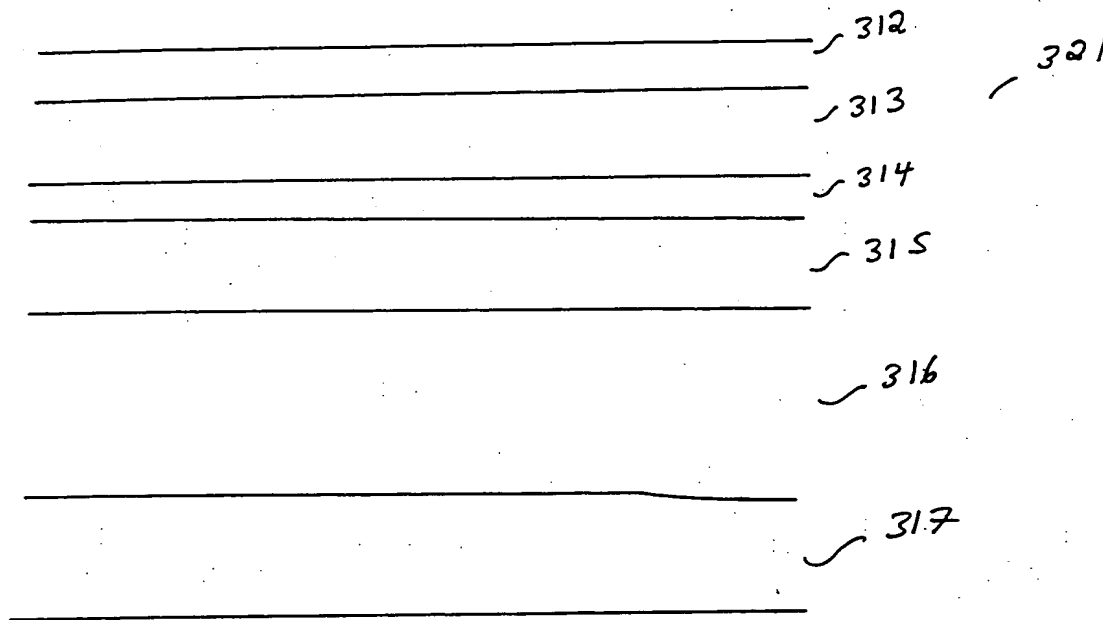
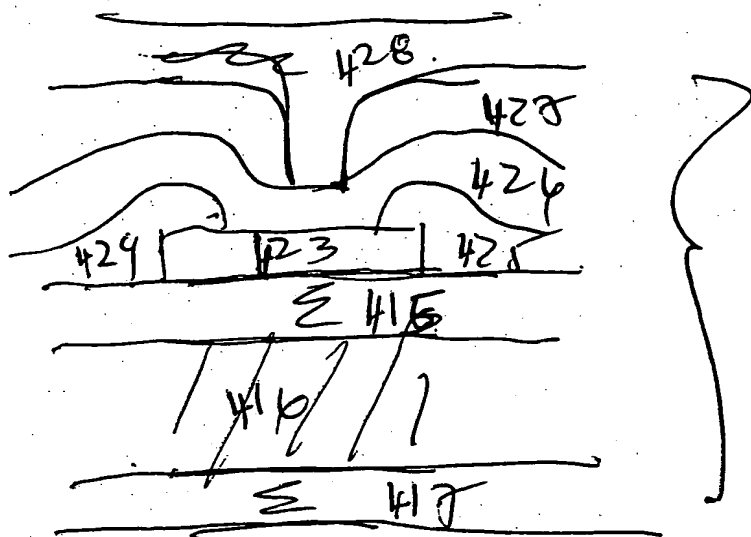


Figure 3



422 bottom gate transistor

figure 4

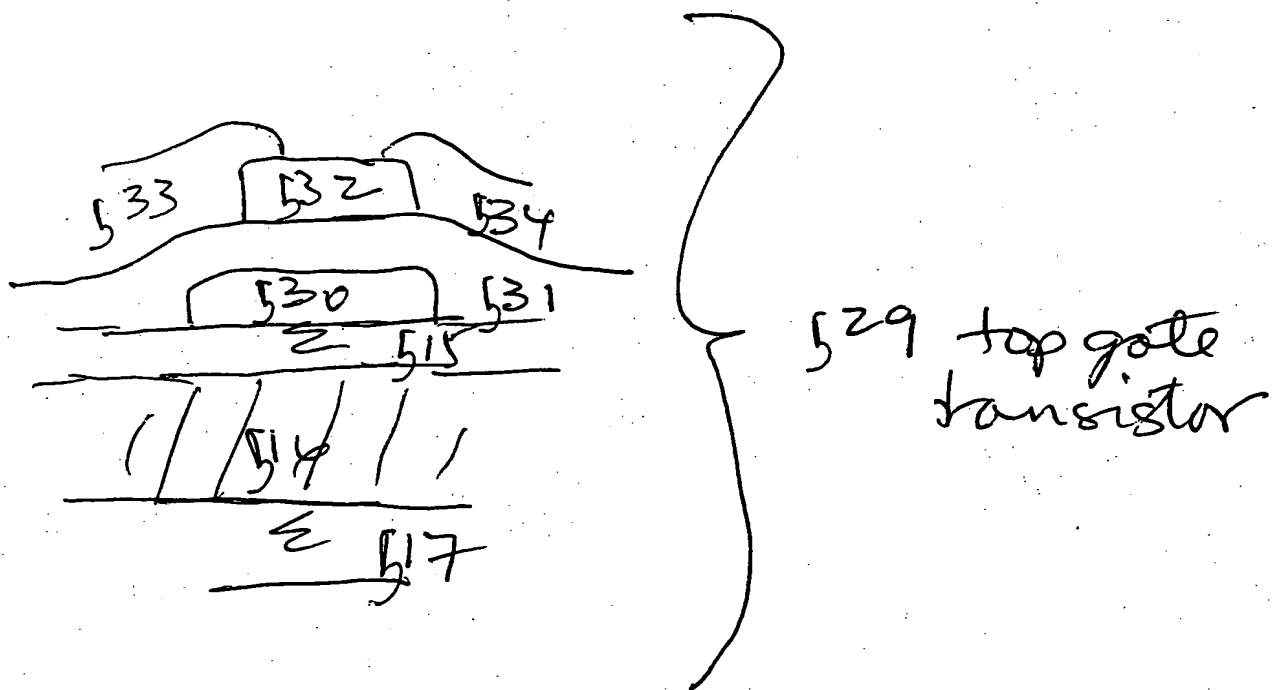


figure 5.-

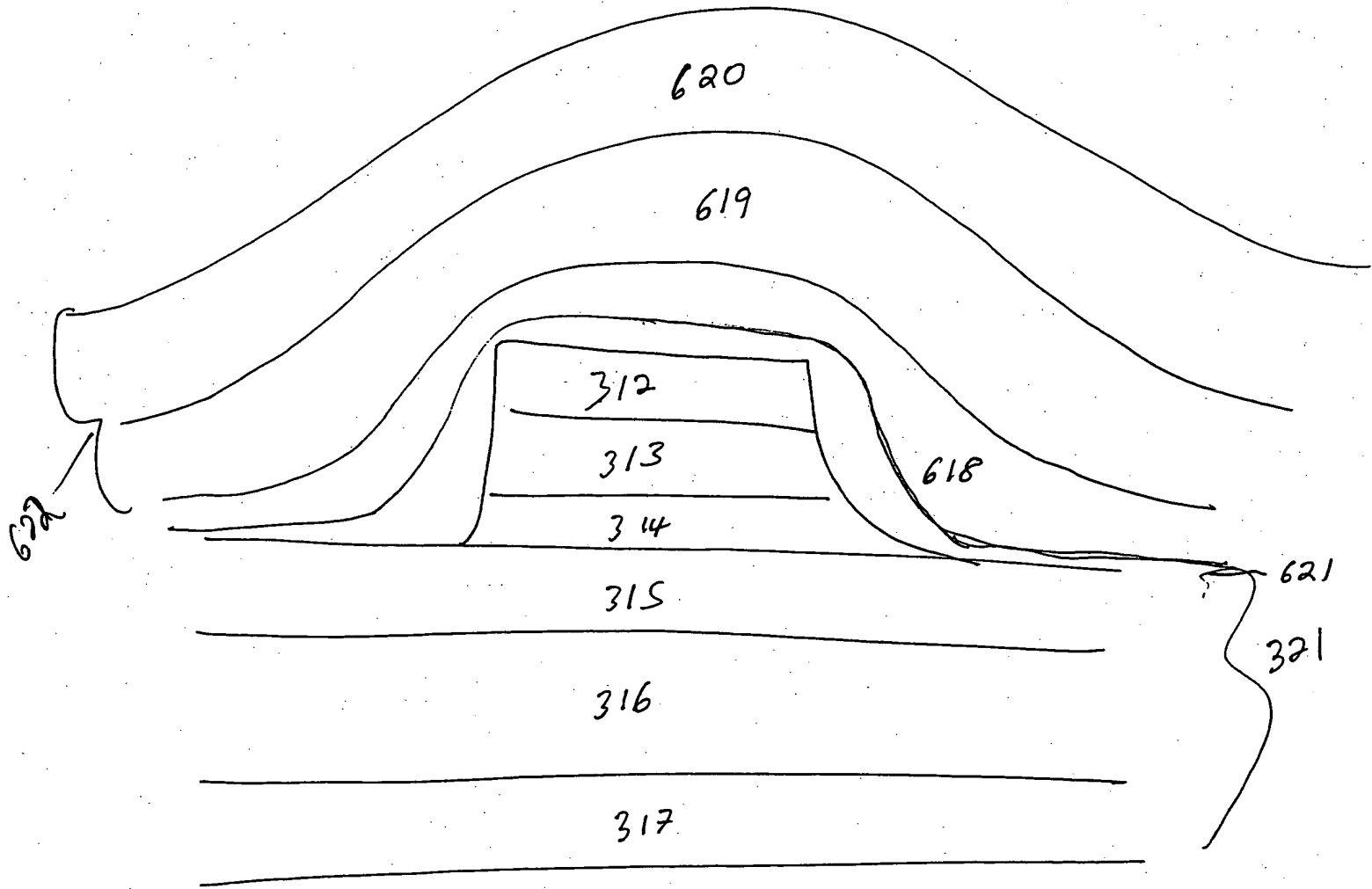


Figure 6

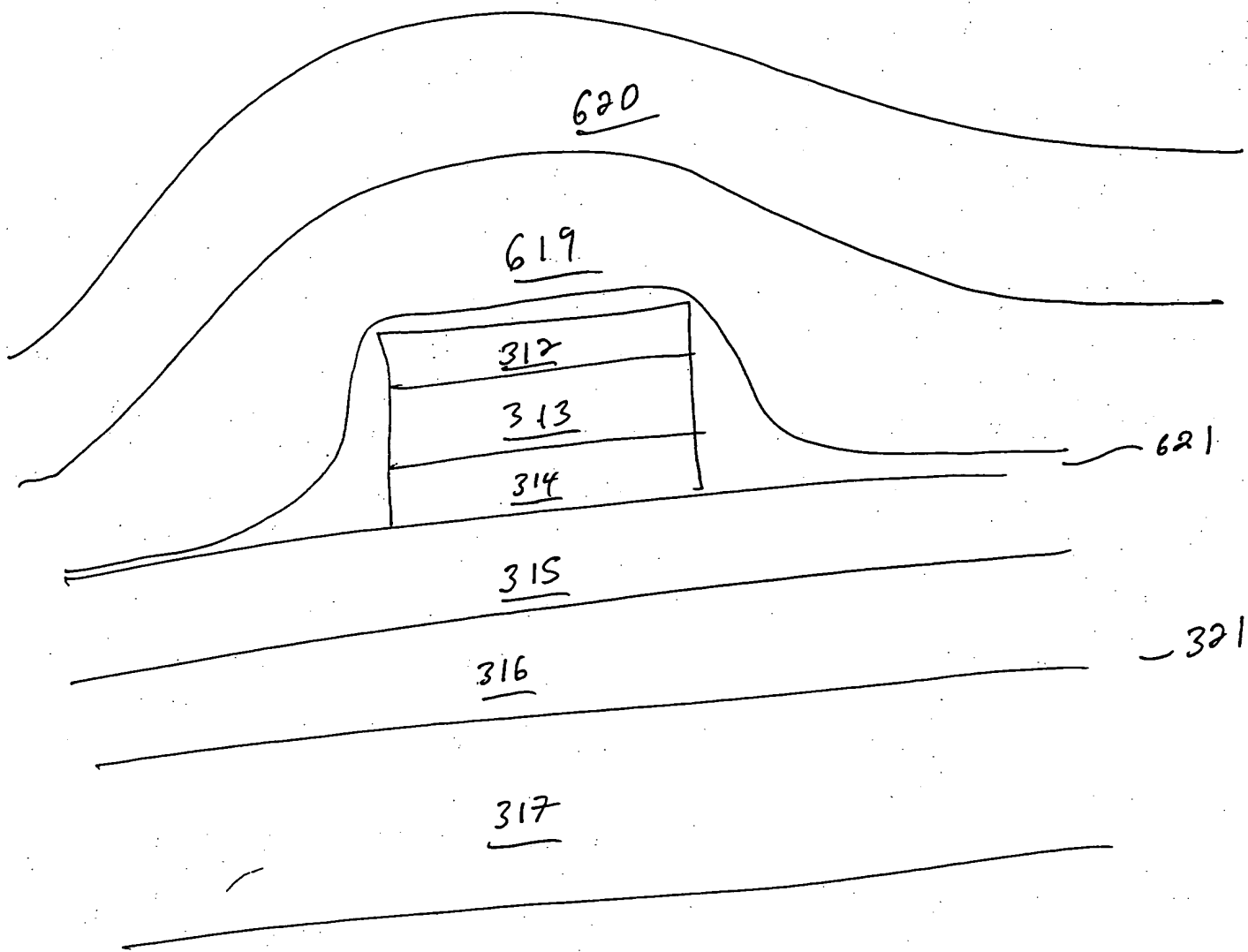


Figure 7

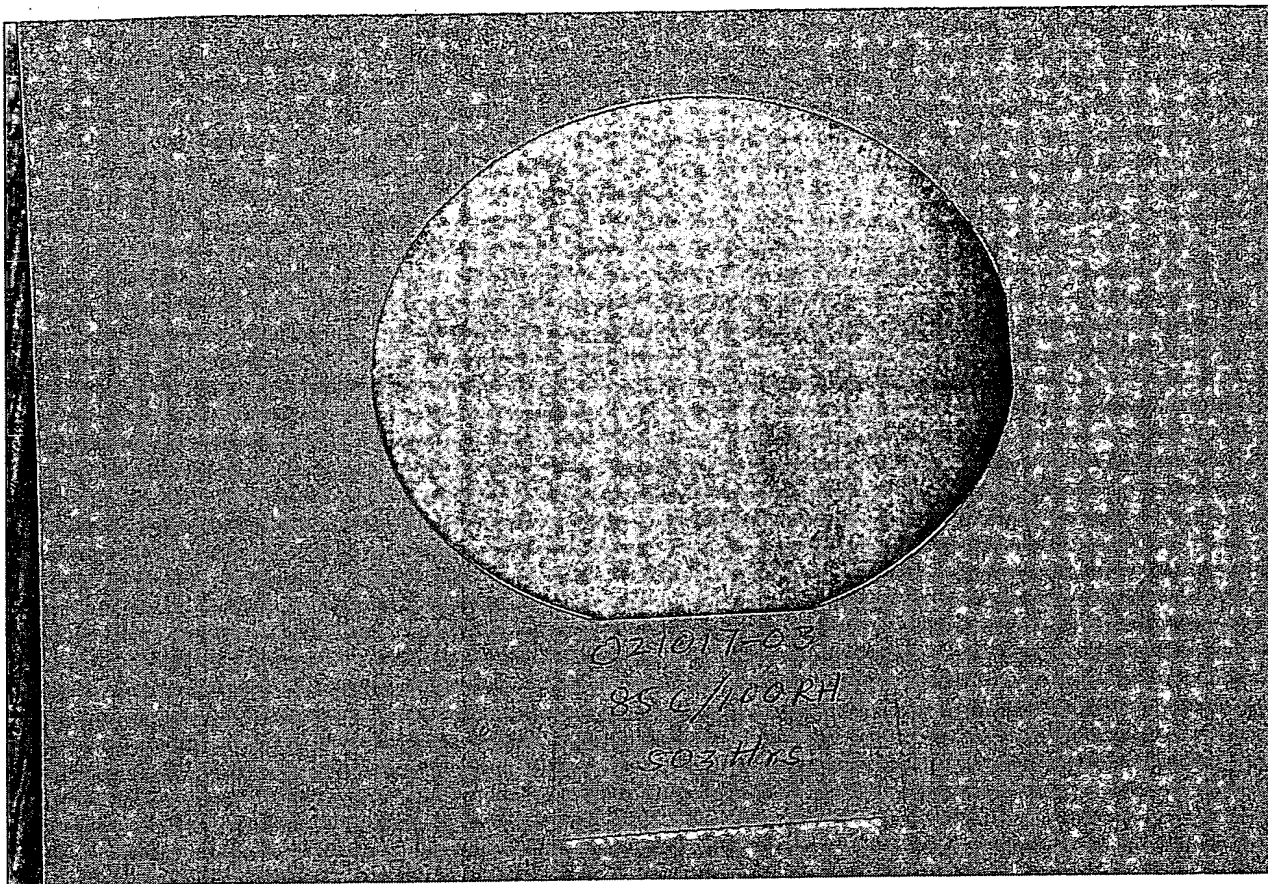


FIG. 8

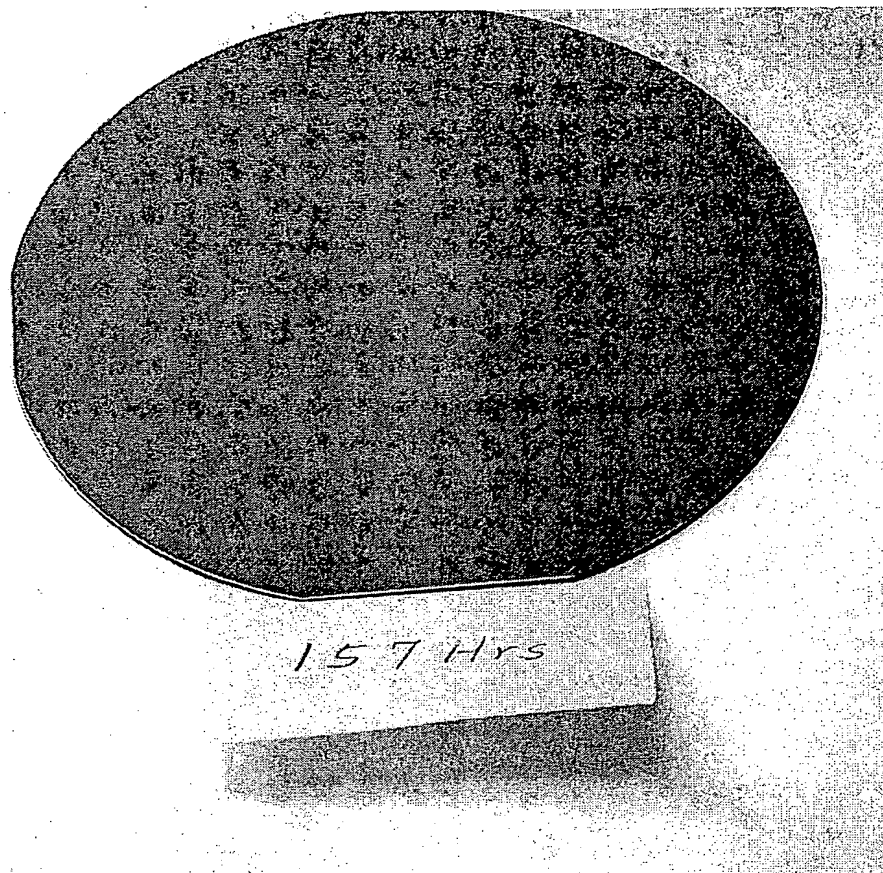


FIG. 9

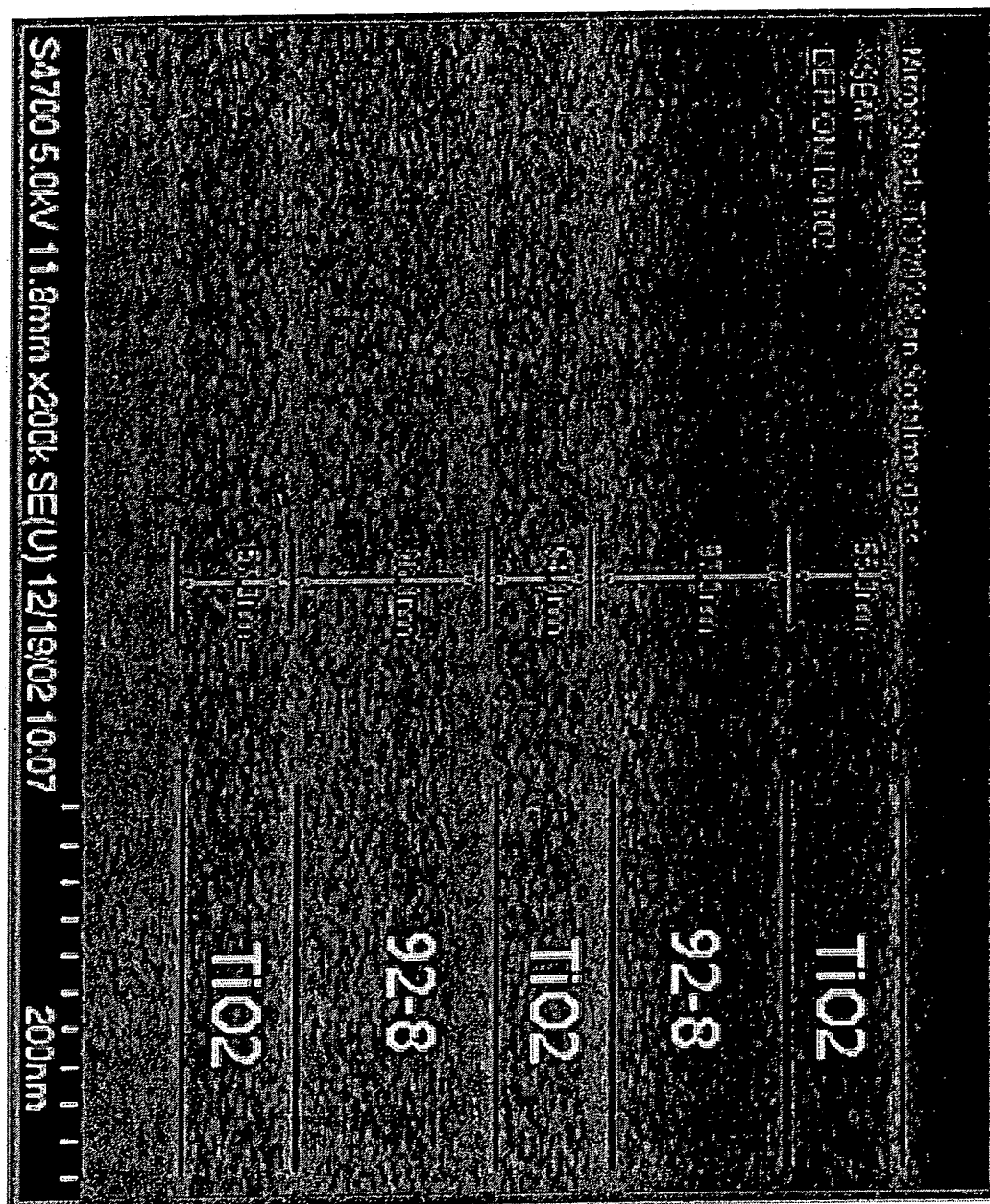


FIG. 10

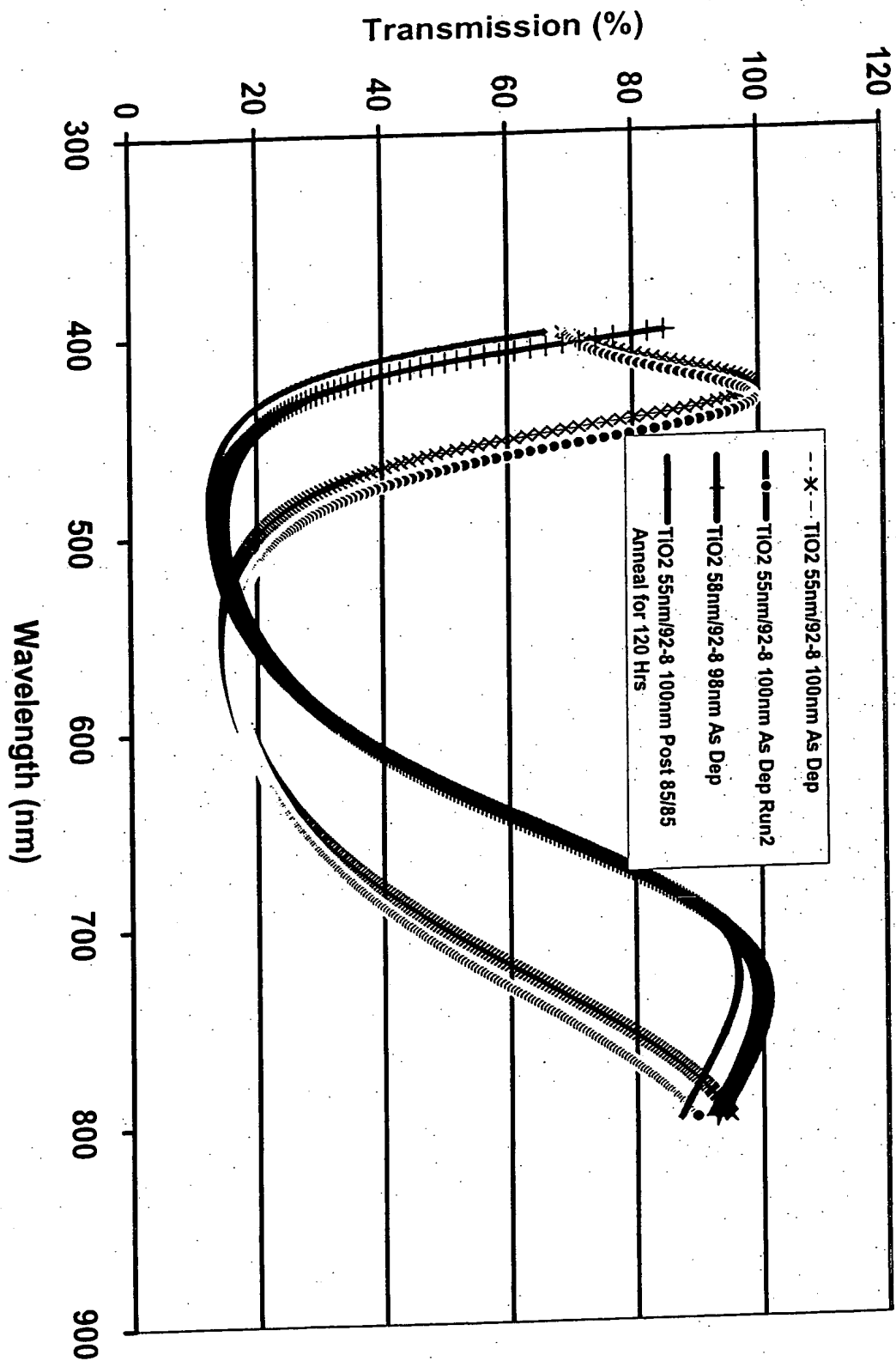


Figure 11

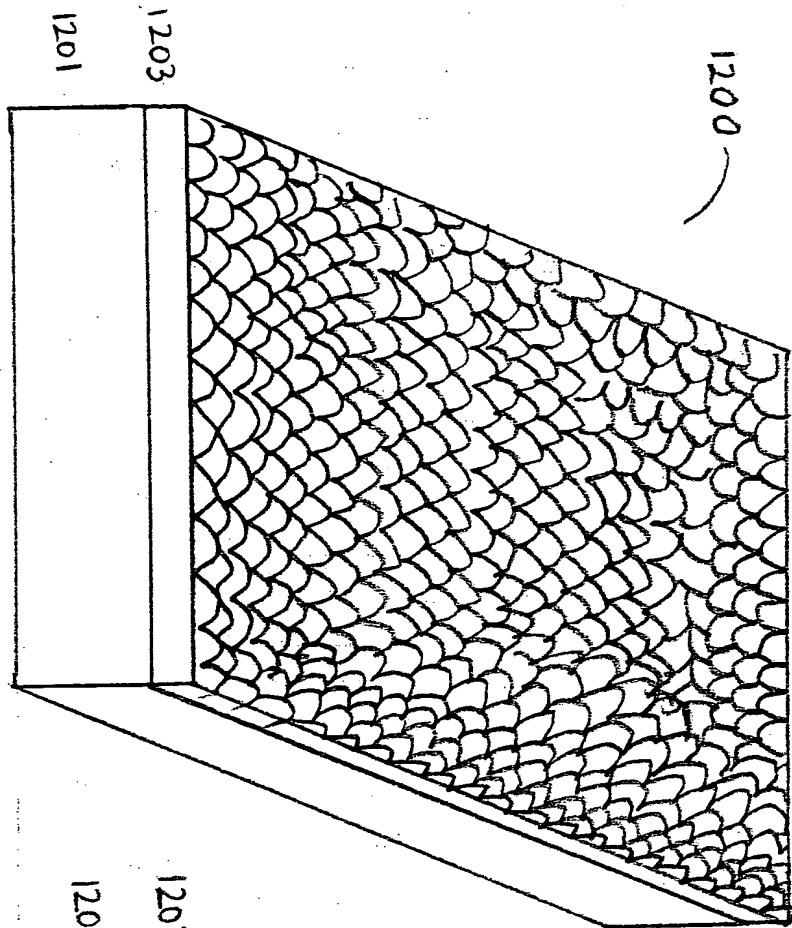


Fig 12A

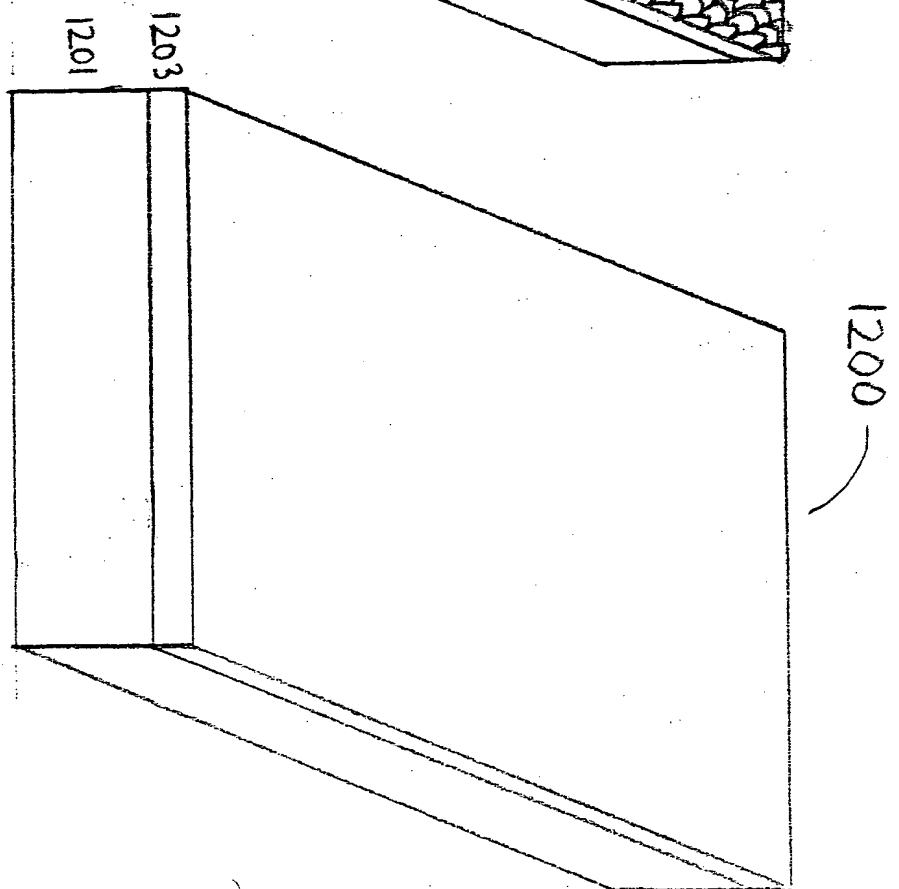


Fig 12B

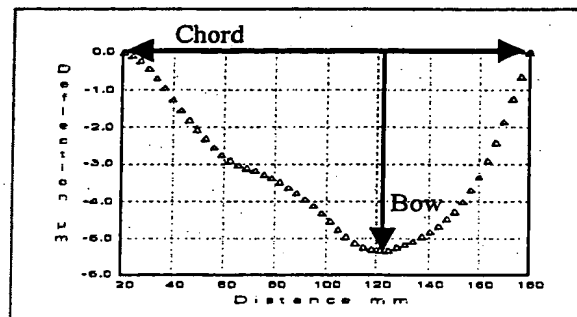
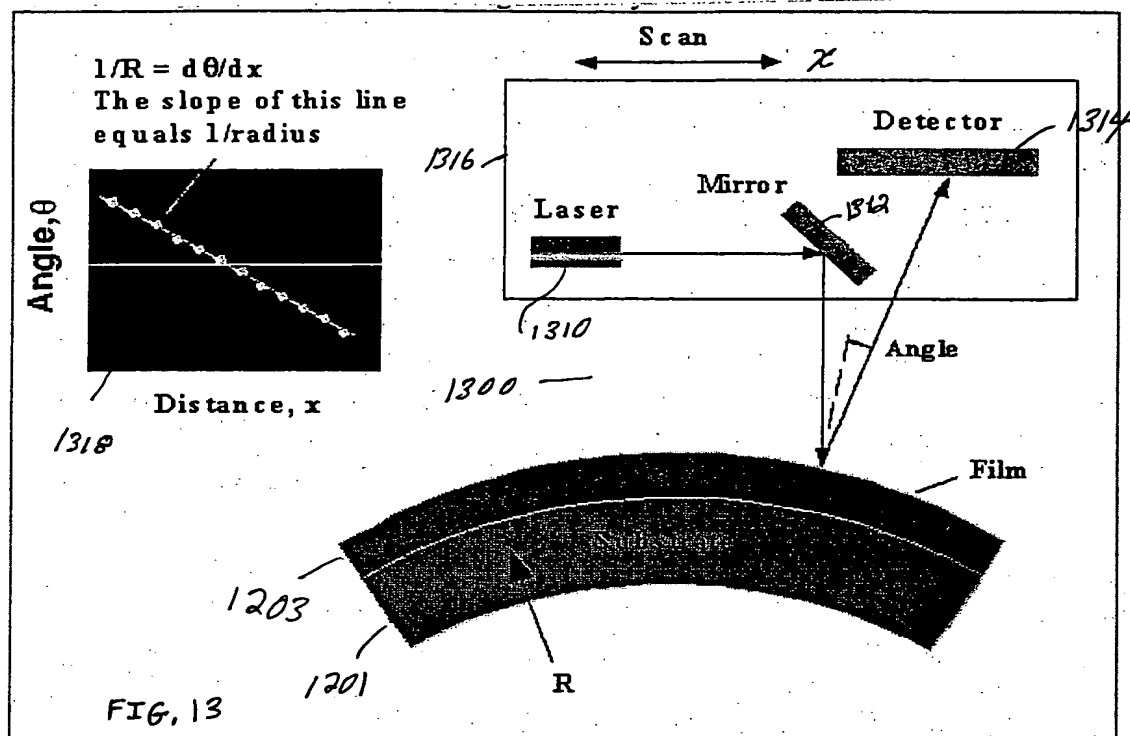


FIG. 14

Stress Chart for Thermal Cycle of Films

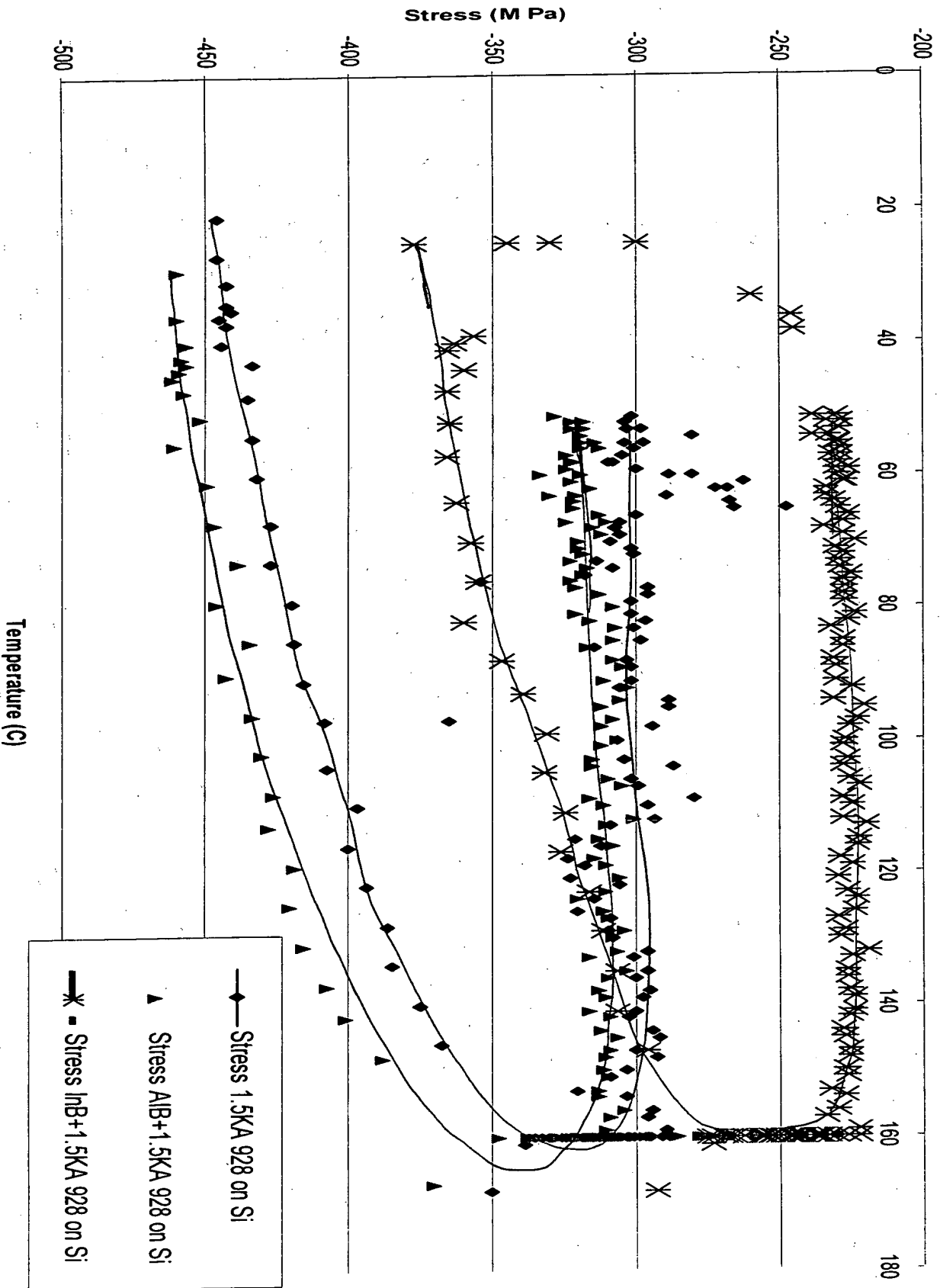


FIG. 15

Fig 16A

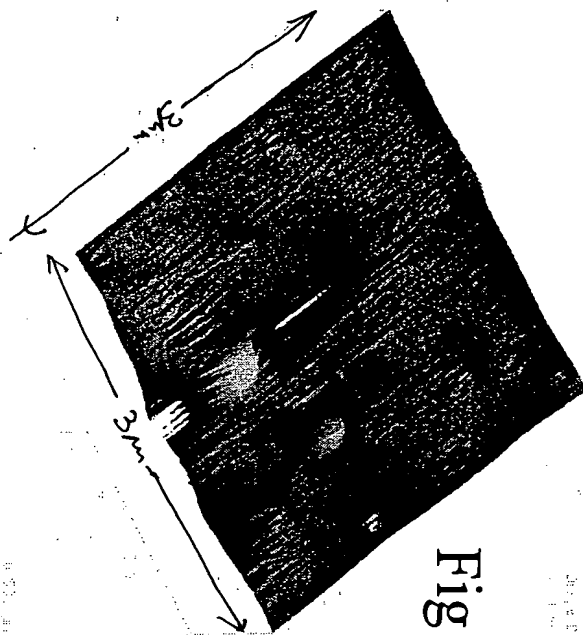


Fig 16C

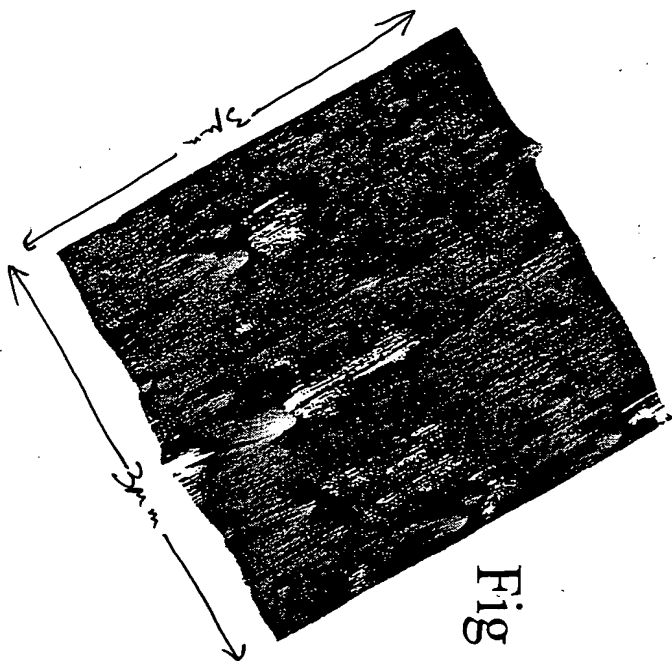


Fig 16B

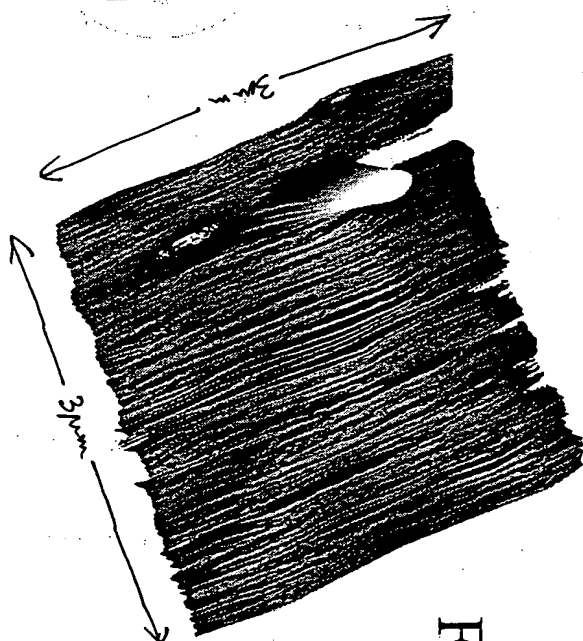


Fig 16D

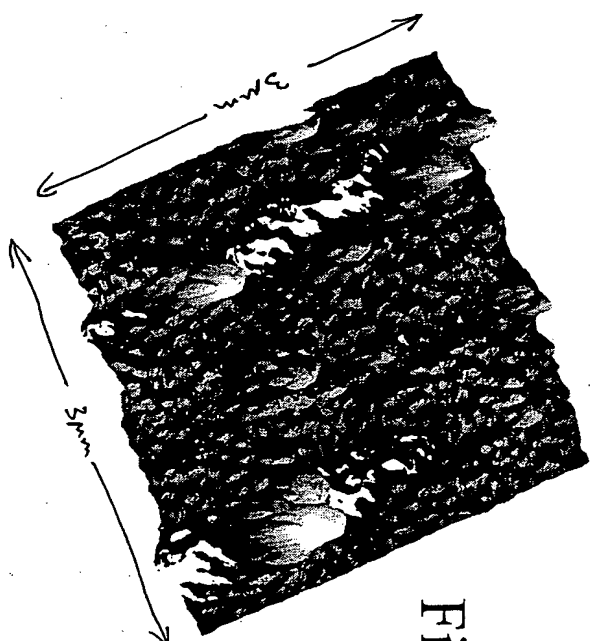
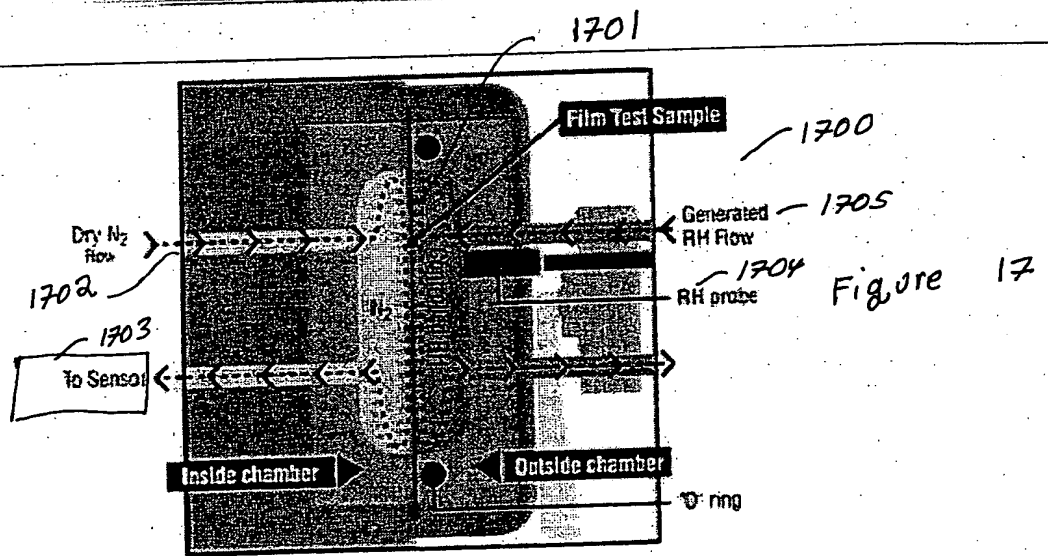


Figure 20

2002

2001



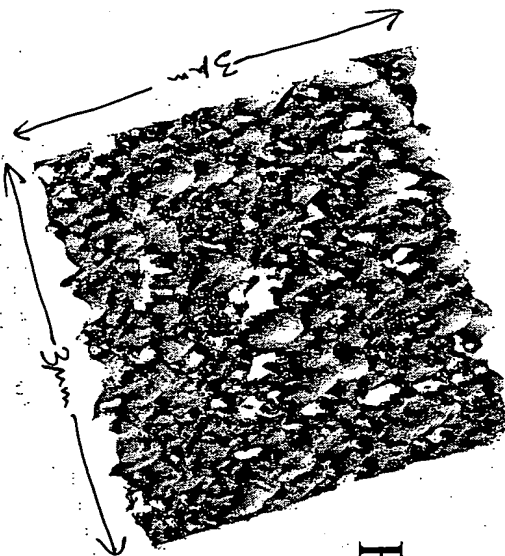


Fig18A

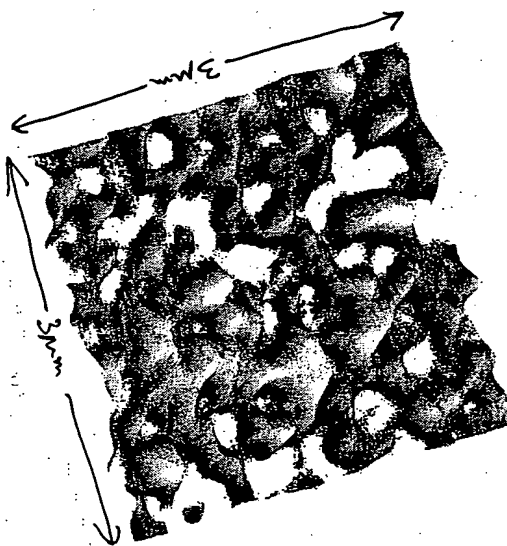
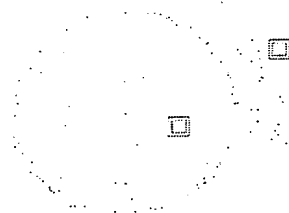


Fig18B

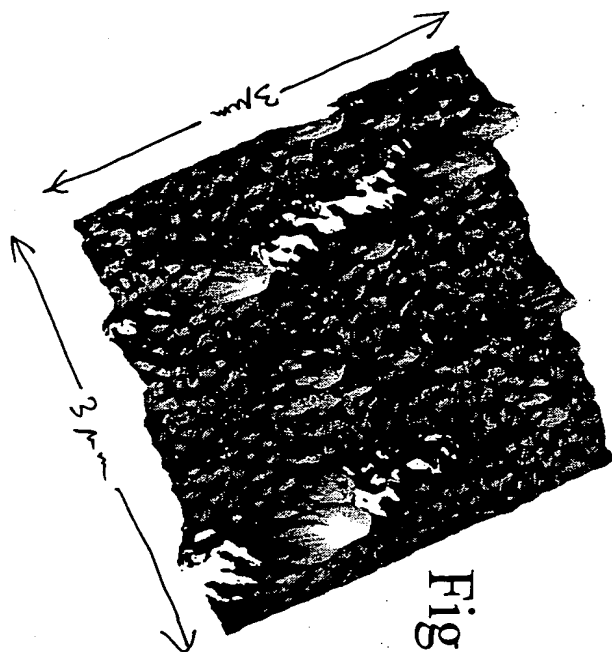
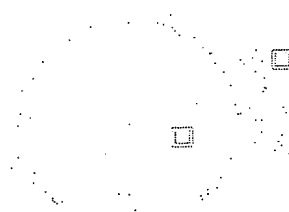


Fig18C

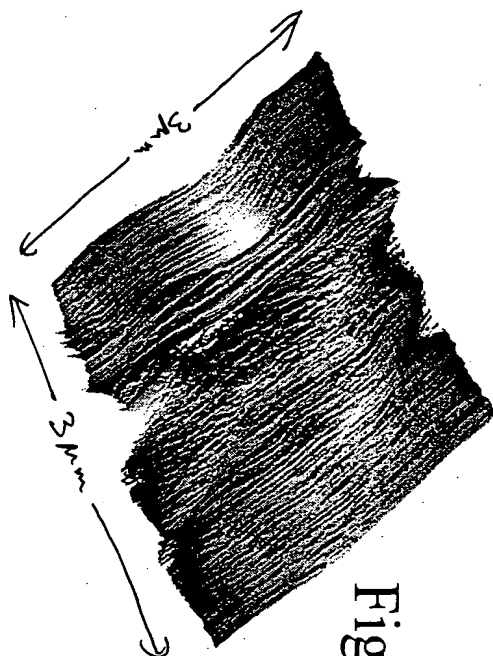
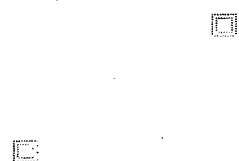


Fig18D



Fig 19A

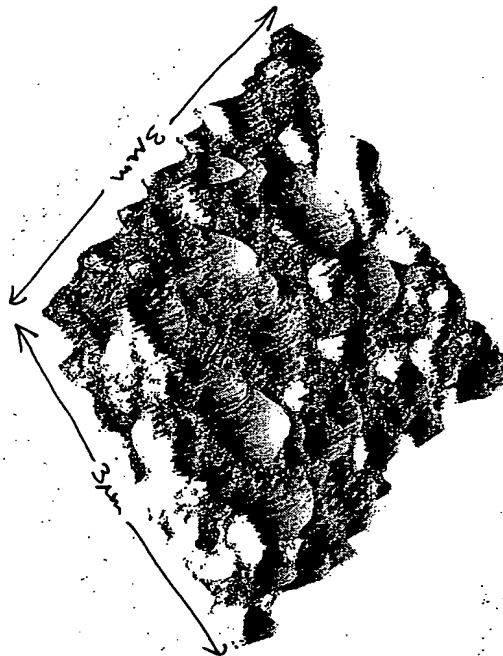


Fig 19B

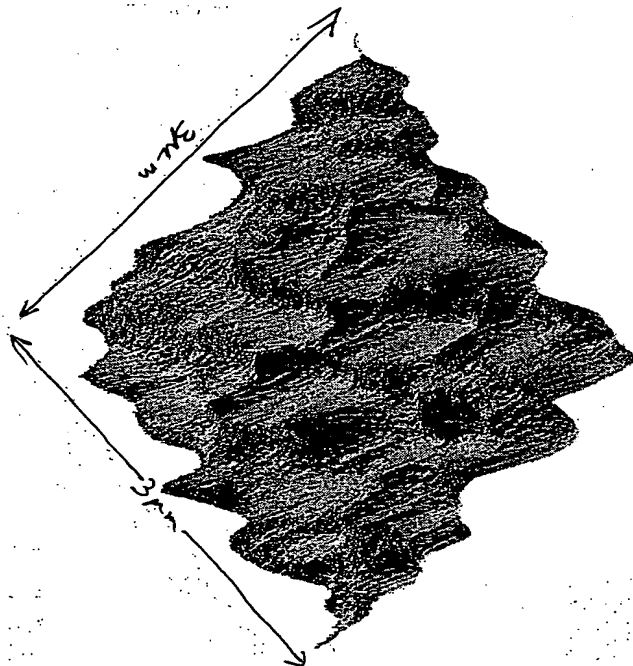


Fig 21A

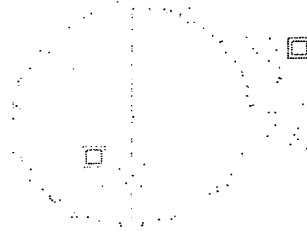
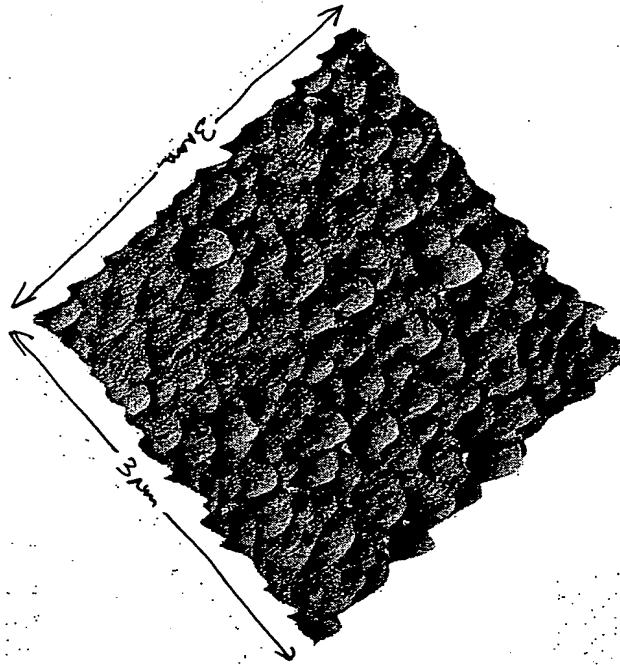


Fig 21B

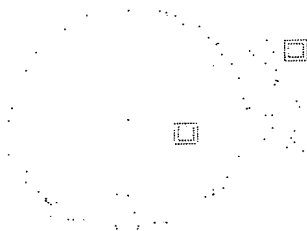
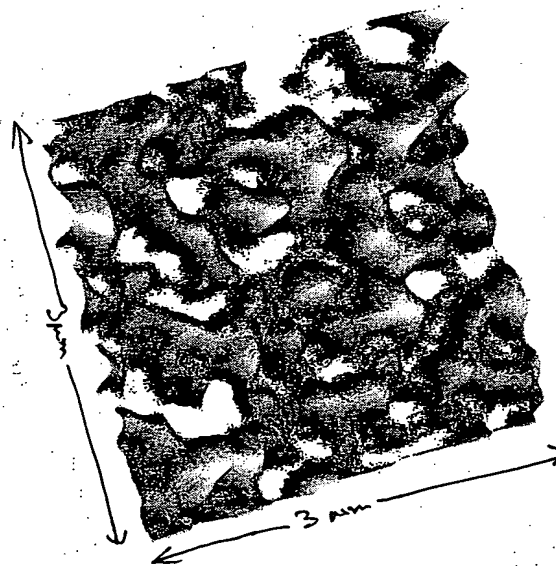


Fig22-A

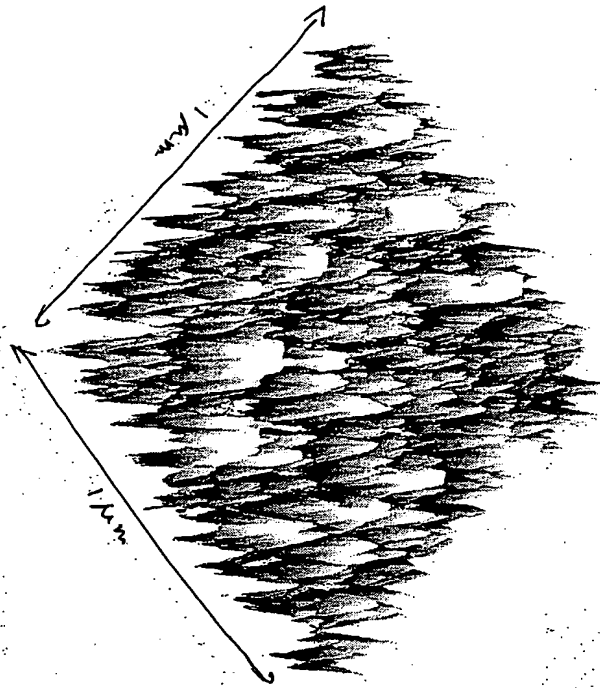


Fig22-B

